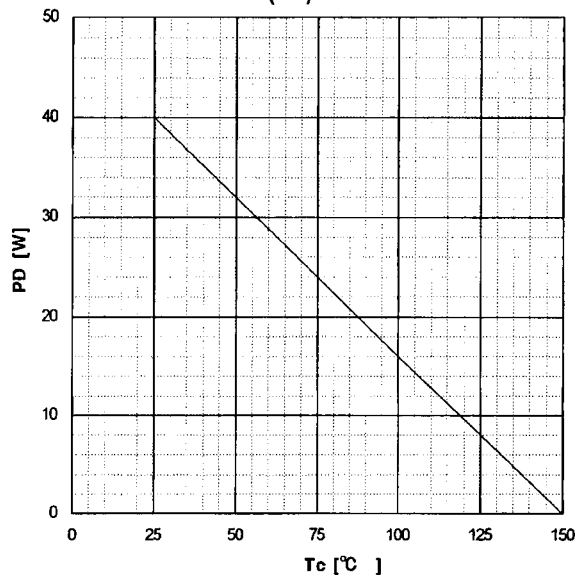


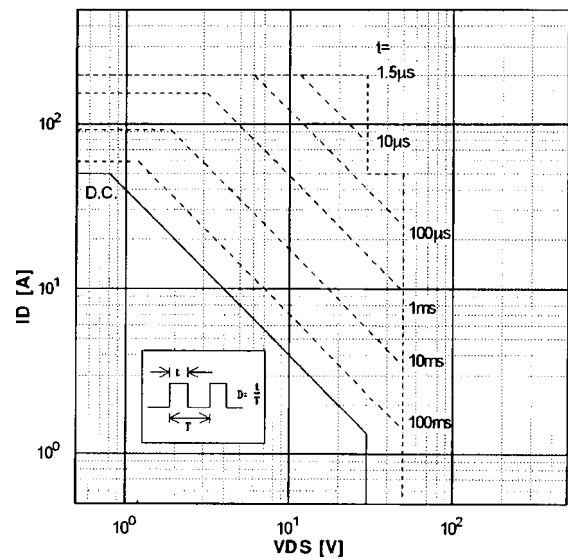
FAP-III B SERIES

Characteristics

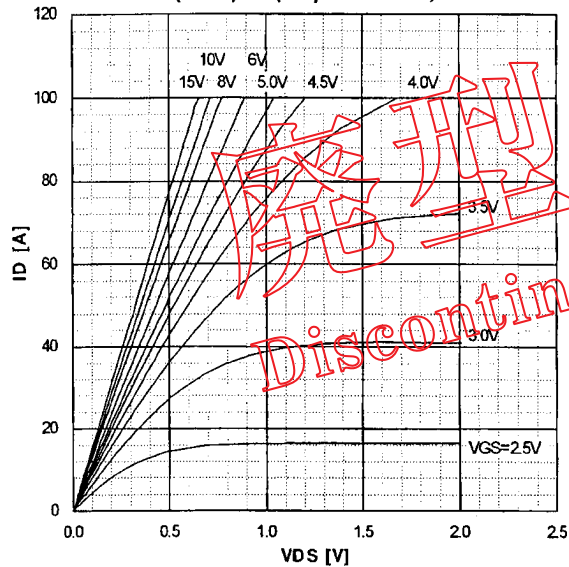
Power Dissipation
 $PD=f(T_c)$



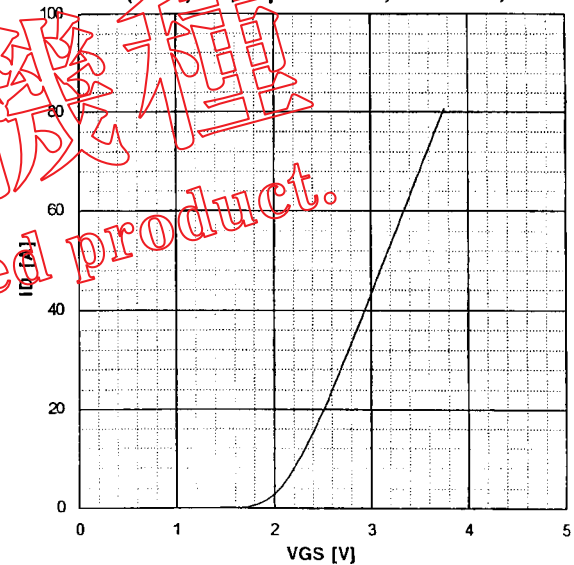
Safe operating area
 $ID=f(V_{DS}): D=0.01, T_c=25^\circ\text{C}$



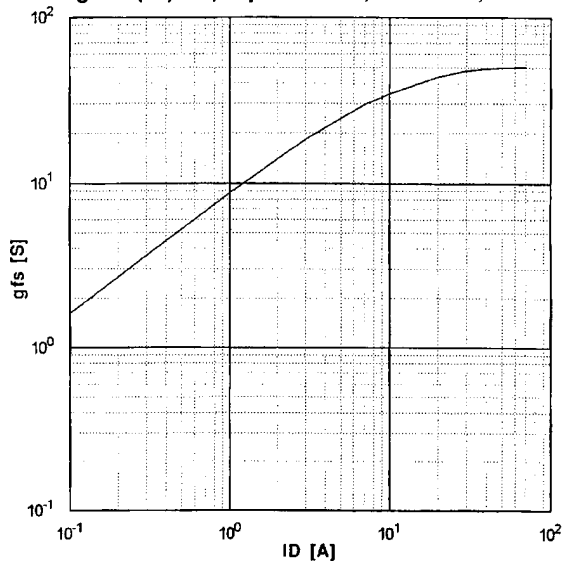
Typical Output Characteristics
 $ID=f(V_{DS}): 80\mu\text{s pulse test}, T_{ch}=25^\circ\text{C}$



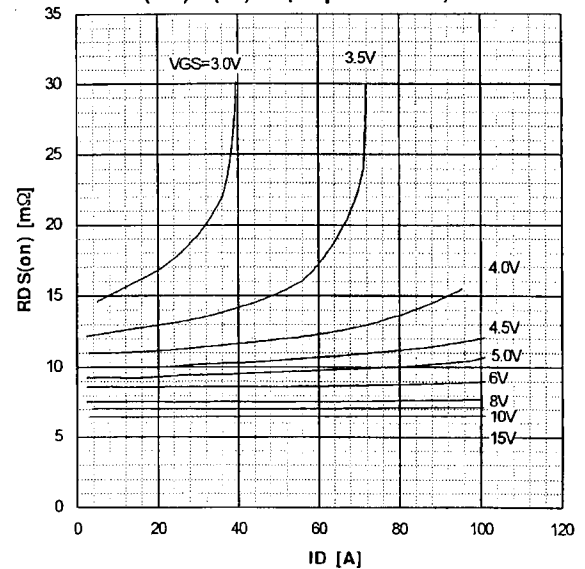
Typical Transfer Characteristic
 $ID=f(V_{GS}): 80\mu\text{s pulse test}, V_{DS}=25V, T_{ch}=25^\circ\text{C}$



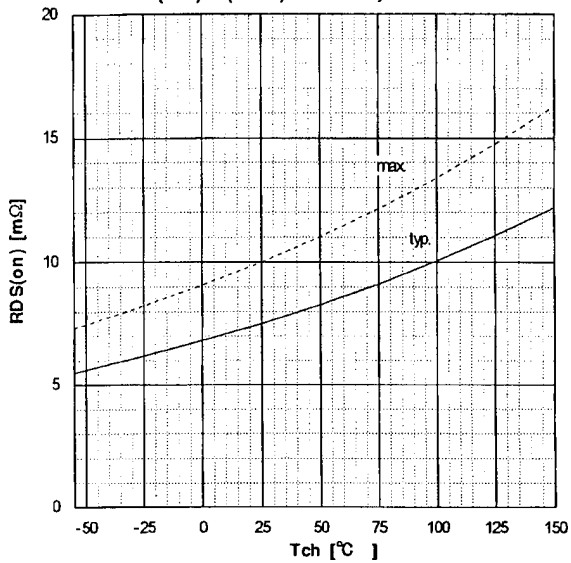
Typical Transconductance
 $g_{fs}=f(ID): 80\mu\text{s pulse test}, V_{DS}=25V, T_{ch}=25^\circ\text{C}$



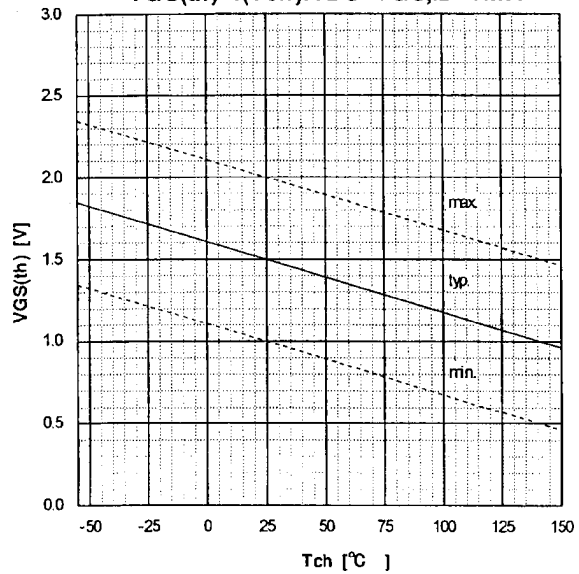
Typical Drain-Source on-state Resistance
 $R_{DS(on)}=f(ID): 80\mu\text{s pulse test}, T_{ch}=25^\circ\text{C}$



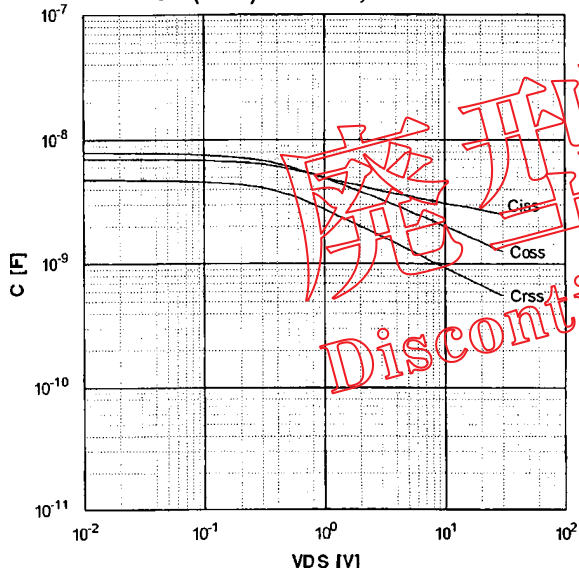
Drain-Source On-state Resistance
 $R_{DS(on)} = f(T_{ch})$; $I_D = 25A, V_{GS} = 10V$



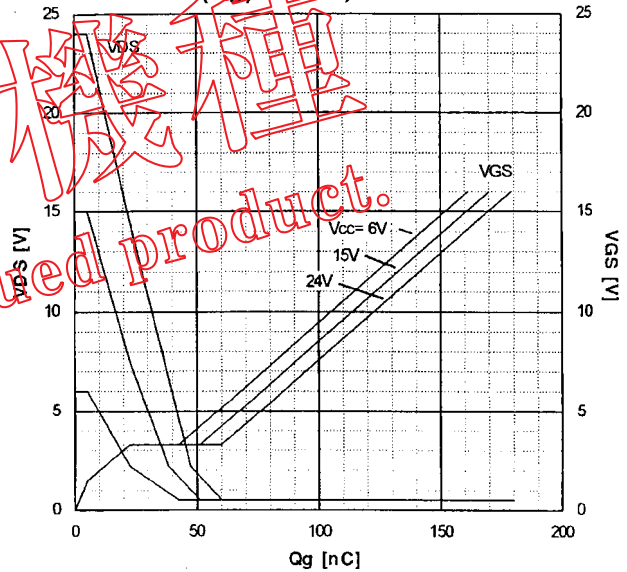
Gate Threshold Voltage
 $V_{GS(th)} = f(T_{ch})$; $V_{DS} = V_{GS}, I_D = 1mA$



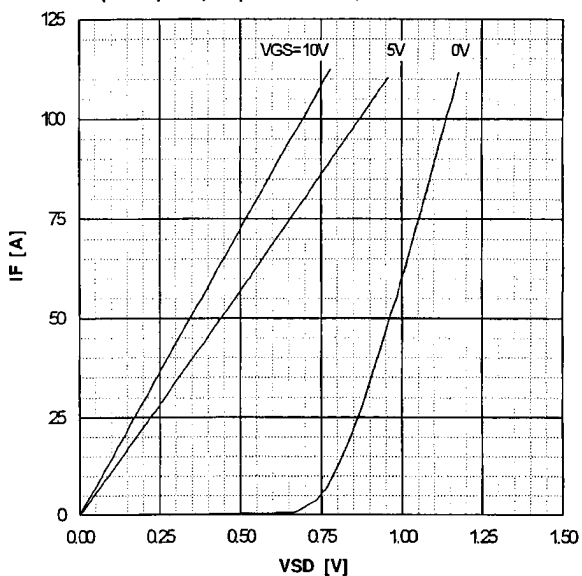
Typical Capacitance
 $C = f(V_{DS})$; $V_{GS} = 0V, f = 1MHz$



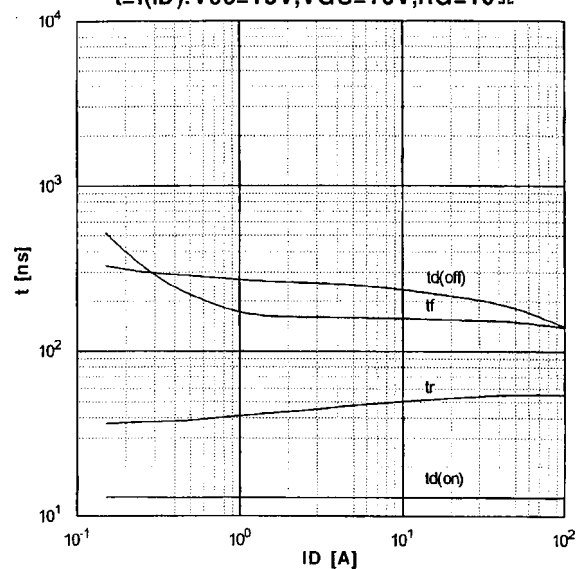
Typical Gate Charge Characteristics
 $V_{GS} = f(Q_g)$; $I_D = 50A, T_{ch} = 25^{\circ}C$



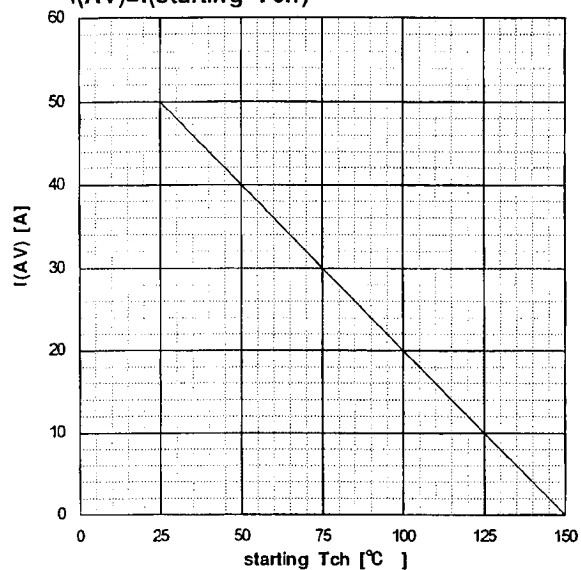
Typical Forward Characteristics of Reverse Diode
 $I_F = f(V_{SD})$; 80 μs pulse test, $T_{ch} = 25^{\circ}C$



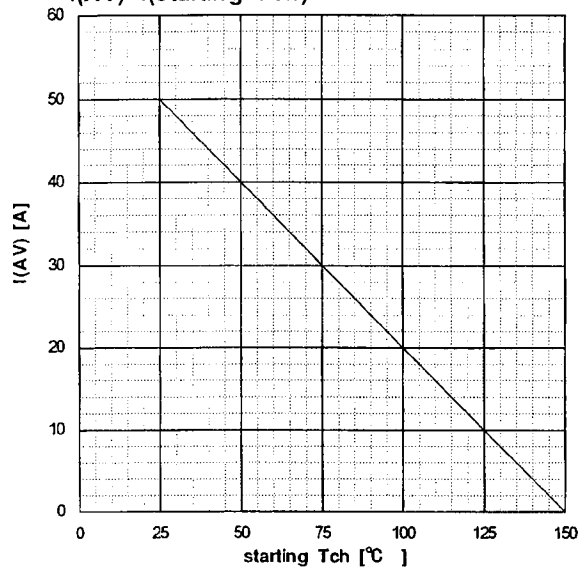
Typical Switching Characteristics vs. I_D
 $t = f(I_D)$; $V_{CC} = 15V, V_{GS} = 10V, R_G = 10\Omega$



Maximum Avalanche Current vs. starting Tch
 $I(AV)=f(\text{starting Tch})$



Maximum Avalanche Current vs. starting Tch
 $I(AV)=f(\text{starting Tch})$



Transient Thermal impedance
 $Z_{th}(ch-c)=f(t)$ parameter: $D=t/T$

